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|-----------------------------------|--|--------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination BATNI ET AL. | |
| | | Examiner CongVan Tran | Art Unit 2683 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-6,937,850 B2 | 08-2005 | Lippelt, Hans-Peter | 455/408 |
| | B | US-6,829,473 B2 | 12-2004 | Raman et al. | 455/406 |
| | C | US-6,816,721 B1 | 11-2004 | Rudisill, Luther | 455/406 |
| | D | US-6,788,927 B2 | 09-2004 | Pohutsky et al. | 455/406 |
| | E | US-6,684,072 B1 | 01-2004 | Anvekar et al. | 455/432.1 |
| | F | US-6,397,055 B1 | 05-2002 | McHenry et al. | 455/408 |
| | G | US-6,226,364 B1 | 05-2001 | O'Neil, Douglas R. | 379/114.2 |
| | H | US-2005/0164707 A1 | 07-2005 | Batni et al. | 455/445 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
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| | R | | | | | |
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NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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